

INTERNATIONAL STANDARD

NORME INTERNATIONALE

**Integrated circuits – Measurement of electromagnetic immunity –
Part 1: General conditions and definitions**

**Circuits intégrés – Mesure de l'immunité électromagnétique –
Partie 1: Conditions générales et définitions**





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**INTEGRATED CIRCUITS –
MEASUREMENT OF ELECTROMAGNETIC IMMUNITY –****Part 1: General conditions and definitions**

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International Standard IEC 62132-1 has been prepared by subcommittee 47A: Integrated circuits, of IEC technical committee 47: Semiconductor devices.

This second edition cancels and replaces the first edition published in 2006 and constitutes a technical revision.

This edition includes the following significant technical changes with respect to the previous edition:

- a) frequency range of 150 kHz to 1 GHz has been deleted from the title;
- b) frequency step above 1 GHz has been added in Table 2 in 7.4.1;
- c) IC performance classes in 8.3 have been modified;
- d) Table A.1 was divided into two tables, and references to IEC 62132-8 and IEC 62132-9 have been added in the new Table A.2 in Annex A.